

# **OptiMOS™2** Power-Transistor

#### **Features**

- N-channel, logic level
- Very low gate charge  $x R_{DS(on)}$  product (FOM)
- Very low on-resistance R DS(on)
- 150 °C operating temperature
- Pb-free lead plating; RoHS compliant; Halogen Free
- Qualified according to JEDEC<sup>1)</sup> for target application
- Ideal for high-frequency switching and synchronous rectification
- Halogen-free according to IEC61249-2-21





Туре	Package	Marking
BSC105N10LSF G	PG-TDSON-8	105N10LS



## **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit	
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	90	А	
		T <sub>C</sub> =100 °C	57	1	
		T <sub>A</sub> =25 °C, R <sub>thJA</sub> =50 K/W <sup>2)</sup>	11.4		
Pulsed drain current <sup>3)</sup>	/ <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	360	1	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 Ω	377	mJ	
Gate source voltage	V <sub>GS</sub>		±20	V	
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	156	w	
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C	
IEC climatic category; DIN IEC 68-1			55/150/56		

### **Product Summary**

V <sub>DS</sub>	100	٧
R <sub>DS(on),max</sub>	10.5	mΩ
ID	90	Α

#### PG-TDSON-8





# BSC105N10LSF G

Parameter	Symbol	Conditions	Values			Unit
		min.	typ.	max.		
Thermal characteristics						
Thermal resistance, junction - case	R <sub>thJC</sub>	bottom	-	-	0.8	K/W
		top	-	-	18	1
Thermal resistance,	R <sub>thJA</sub> minimal footprint 6	62				
junction - ambient		6 cm2 cooling area <sup>2)</sup>	-	-	50	

**Electrical characteristics,** at  $T_{\rm j}$ =25 °C, unless otherwise specified

### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	100	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 110 \ \mu {\rm A}$	1.2	1.85	2.4	
Zero gate voltage drain current	/ <sub>DSS</sub>	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C	1	0.01	1	μΑ
		V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	1	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5 V, I <sub>D</sub> =25 A	1	11.1	14.1	mΩ
		V <sub>GS</sub> =10 V, I <sub>D</sub> =50 A	-	8	10.5	
Gate resistance	R <sub>G</sub>		1	1.3	-	Ω
Transconductance	g fs	V <sub>DS</sub>  >2 I <sub>D</sub>  R <sub>DS(on)max</sub> , I <sub>D</sub> =50 A	36	72	-	s

<sup>1)</sup>J-STD20 and JESD22

 $<sup>^{2)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.

<sup>3)</sup> see figure 3



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	2900	3900	pF
Output capacitance	C oss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz	-	730	970	
Reverse transfer capacitance	C <sub>rss</sub>		-	14	-	
Turn-on delay time	t <sub>d(on)</sub>		-	15	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =50 V, V <sub>GS</sub> =10 V,	-	26	-	1
Turn-off delay time	$t_{\text{d(off)}}$	/ <sub>D</sub> =25 A, R <sub>G</sub> =1.6 Ω	-	37	-	1
Fall time	t <sub>f</sub>	]	-	8	-	1
Gate Charge Characteristics <sup>4)</sup>						
Gate to source charge	Q <sub>gs</sub>		-	10	-	nC
Gate to drain charge	Q <sub>gd</sub>	$V_{DD}$ =50 V, $I_{D}$ =25 A, $V_{GS}$ =0 to 10 V - 12	7	1		
Switching charge	Q sw		1			
Gate charge total	Qg		-	40	53	
Gate plateau voltage	V <sub>plateau</sub>		-	3.5	-	V
Output charge	Q <sub>oss</sub>	V <sub>DD</sub> =50 V, V <sub>GS</sub> =0 V	-	70	94	nC
Reverse Diode	-					
Diode continous forward current	Is	T -25 °C	-	-	90	А
Diode pulse current	/ <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	360	1
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =50 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =50 V, I <sub>F</sub> =25 A,	-	92	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/μs	-	246	-	nC

 $<sup>^{</sup>m 4)}$  See figure 16 for gate charge parameter definition

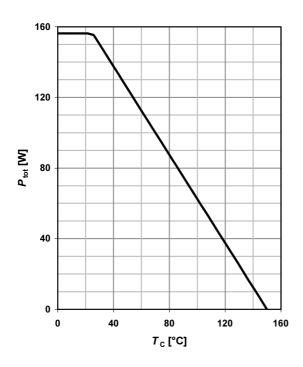


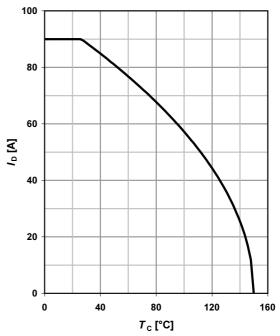
### 1 Power dissipation

# $P_{tot}$ =f( $T_{C}$ )

### 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$

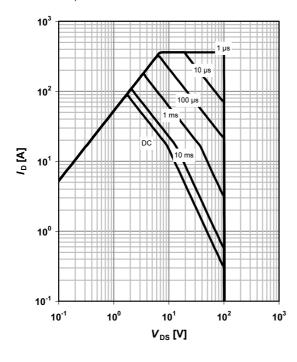




# 3 Safe operating area

$$I_D$$
=f( $V_{DS}$ );  $T_C$ =25 °C;  $D$ =0

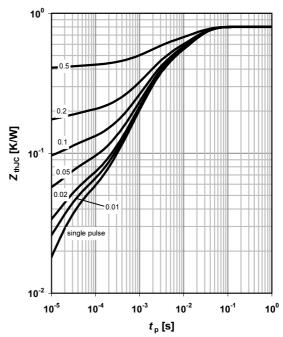
parameter:  $t_p$ 



# 4 Max. transient thermal impedance

$$Z_{thJC}$$
=f( $t_p$ )

parameter:  $D = t_p/T$ 

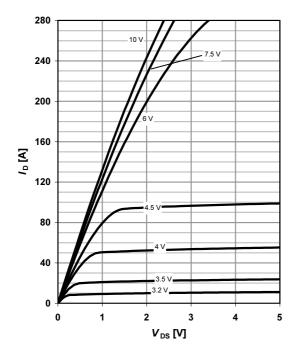




# 5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 \text{ °C}$ 

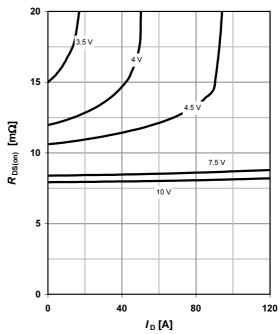
parameter:  $V_{\rm GS}$ 



### 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

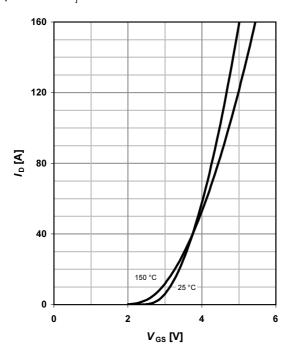
parameter: V<sub>GS</sub>



# 7 Typ. transfer characteristics

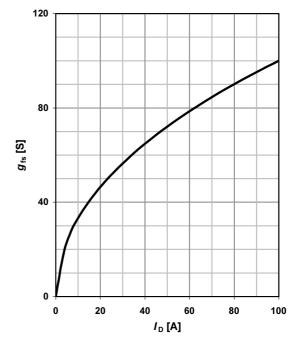
 $I_{D}$ =f( $V_{GS}$ );  $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$ 

parameter:  $T_j$ 



# 8 Typ. forward transconductance

$$g_{fs}$$
=f( $I_D$ );  $T_j$ =25 °C





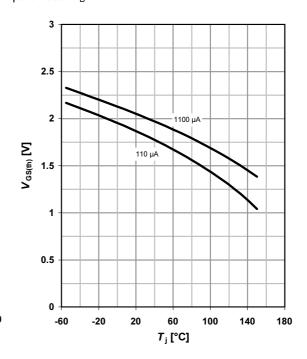
#### 9 Drain-source on-state resistance

 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =25 A;  $V_{GS}$ =10 V

# 

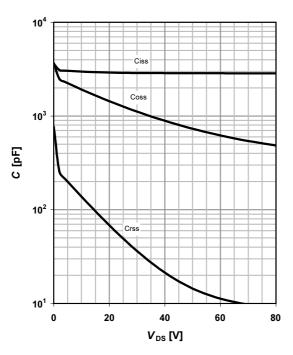
# 10 Typ. gate threshold voltage

 $V_{\rm GS(th)}$ =f( $T_{\rm j}$ );  $V_{\rm GS}$ = $V_{\rm DS}$ parameter:  $I_{\rm D}$ 



# 11 Typ. capacitances

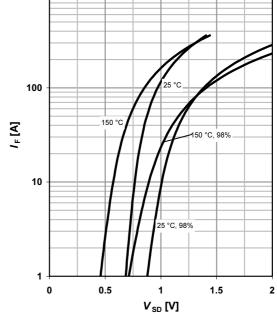
 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 



### 12 Forward characteristics of reverse diode

 $I_{\text{F}} = f(V_{\text{SD}})$ parameter:  $T_{\text{j}}$ 

1000

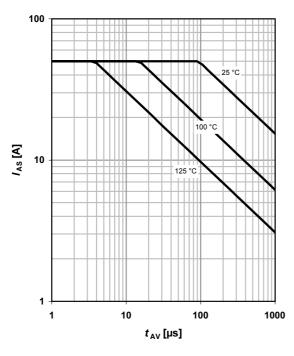




#### 13 Avalanche characteristics

 $I_{AS}$ =f( $t_{AV}$ );  $R_{GS}$ =25  $\Omega$ 

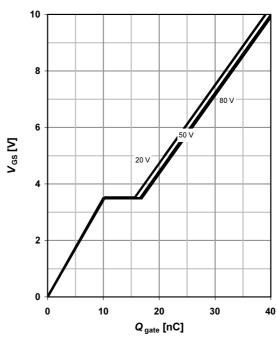
parameter:  $T_{j(start)}$ 



# 14 Typ. gate charge

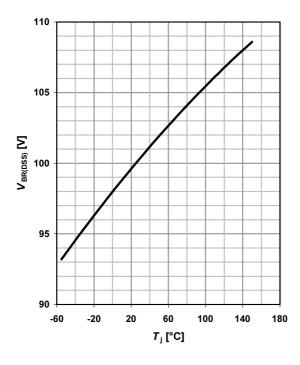
 $V_{\rm GS}$ =f(Q <sub>gate</sub>);  $I_{\rm D}$ =25 A pulsed

parameter:  $V_{\rm DD}$ 

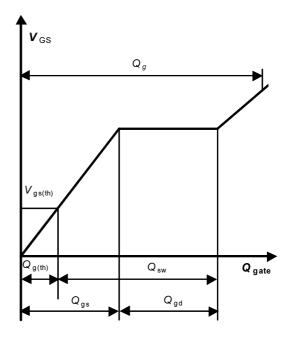


# 15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =1 mA

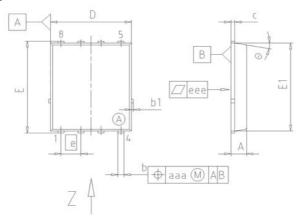


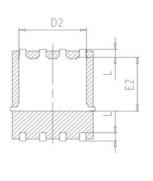
### 16 Gate charge waveforms

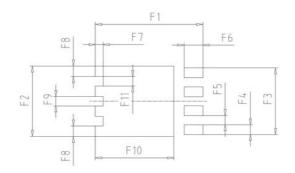


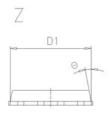


# Package Outline: PG-TDSON-8





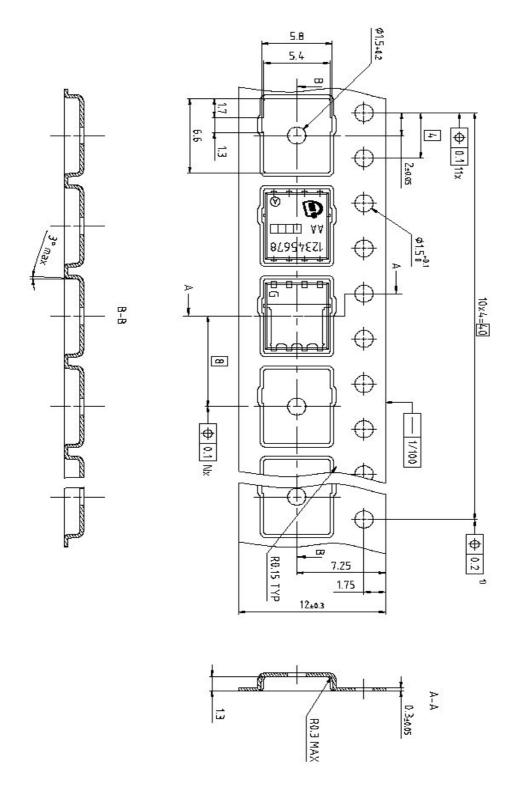




DIM	MILLIM	IETERS	INCI	HES
DIM	MIN	MAX	MIN	MAX
Α	0.90	1.10	0.035	0.043
b	0.34	0.54	0.013	0.021
b1	0.02	0.22	0.001	0.008
С	0.15	0.35	0.006	0.014
D=D1	4.95	5.35	0.195	0.211
D2	4.20	4.40	0.165	0.173
E	5.95	6.35	0.234	0.250
E1	5.70	6.10	0.224	0.240
E2	3.40	3.80	0.134	0.150
е	1.27		0.0	050
N	8		- 3	В
L	0.45	0.65	0.018	0.026
	8.5°	11.5°	8.5°	11.5°
aaa	0.25		0.0	10
eee	0.0	05	0.0	002
F1	6.75	6.95	0.266	0.274
F2	4.60	4.80	0.181	0.189
F3	4.36	4.56	0.172	0.180
F4	0.55	0.75	0.022	0.030
F5	0.52	0.72	0.020	0.028
F6	1.10	1.30	0.043	0.051
F7	0.40	0.60	0.016	0.024
F8	0.60	0.80	0.024	0.031
F9	0.53	0.73	0.021	0.029
F10	4.90	5.10	0.193	0.201
F11	0.53	0.73	0.021	0.029

Z8B000	
SCALE	0
	2.5
0 2.5	
	5mm
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